

**Search Notes**

Application/Control No.

10/617,259

Examiner

German Viana Di Prisco

Applicant(s)/Patent under  
Reexamination

NA ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
370	252	2/6/2008	GV
370	384	2/6/2008	GV
370	392	2/6/2008	GV
370	349	2/6/2008	GV
370	395.2	2/6/2008	GV
370	474	2/6/2008	GV
455	517	2/6/2008	GV
709	247	2/6/2008	GV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
See interference search in search history		2/6/2008	GV

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO and IBM_TDB (see attached search strategy)	2/6/2008	GV
Updated Inventor name and Assignee search in PALM ExPO and EAST	2/6/2008	GV
Updated EPO Database( <a href="http://ep.espacenet.com">http://ep.espacenet.com</a> )	2/6/2008	GV
Updated KIPODatabase ( <a href="http://kposd.kipo.go.kr:8088/up/kpion/">http://kposd.kipo.go.kr:8088/up/kpion/</a> )	2/6/2008	GV
Consulted with Chau Nguyen, Duc Nguyen, Ken Vanderpuye and Rafael Perez-Gutierrez	2/6/2008	GV
congest\$3 with (compress\$3 full) with (header packet)	2/6/2008	GV